

<b>Notice of References Cited</b>	Application/Control No. 10/510,704	Applicant(s)/Patent Under Reexamination HATANAKA ET AL.	
	Examiner John S. Chu	Art Unit 1752	Page 1 of 1

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	C	US-6,399,267 B1	06-2002	Nishimura et al.	430/192
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	M	US-			

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